

Quiz #4

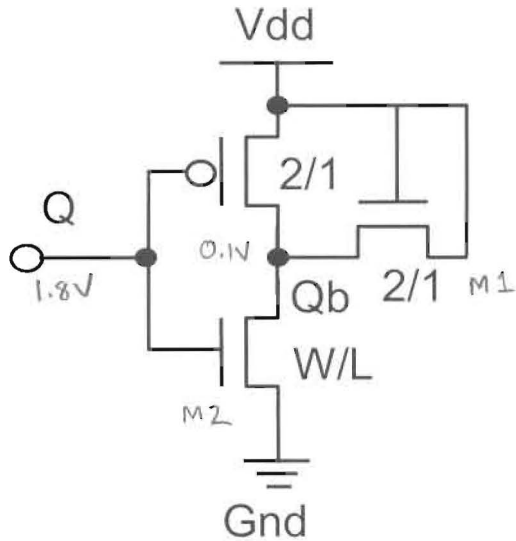
EEEC116

Fall 2011

Name: Solutions

Lab Section: _____

Problem 1 (7 points) Consider the following half-circuit for analyzing the read Static Noise Margin for a memory cell. Find W/L such that node Qb is at 100mV given $V_{DD}=1.8V$, node Q is 1.8V, $V_{T,n}=0.5V$, $\mu_n C_{ox}=3 \times 10^{-4}A/V^2$, $V_{T,p}=-0.5V$, $\mu_p C_{ox} = 1 \times 10^{-4}A/V^2$, $\lambda = 0$, $\gamma = 0$. Show all work to receive full credit.



M1 sat PMOS off (2pts)
M2 lin

KCL @ Qb: (3pts)

$$\begin{aligned} \frac{\mu_n C_{ox}}{2} \left(\frac{W}{L}\right)_1 (V_{DD} - V_{Qb} - V_{T,n})^2 &= \frac{\mu_n C_{ox}}{2} \left(\frac{W}{L}\right)_2 [2(V_{DD} - V_{T,n})V_{Qb} - V_{Qb}^2] \\ \Rightarrow \left(\frac{W}{L}\right)_2 &= \left(\frac{W}{L}\right)_1 \frac{(V_{DD} - V_{Qb} - V_{T,n})^2}{2(V_{DD} - V_{T,n})V_{Qb} - V_{Qb}^2} \quad (1pt.) \\ &= \left(\frac{2}{1}\right) \frac{(1.7V - 0.5V)^2}{2(1.8V - 0.5V)(0.1V) - (0.1V)^2} \\ &= \boxed{11.52} \quad (1pt.) \end{aligned}$$

Problem 2 (3 points) For the following 1 transistor DRAM cell, fill in the boxes labeling the corresponding wires with the appropriate signal names: (1pts ea.)

Q: data storage bit

BL: bit line

WL: word line

